



Cross-calibrating the XMM EPIC effective areas for a default empirical correction

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9 April 2018

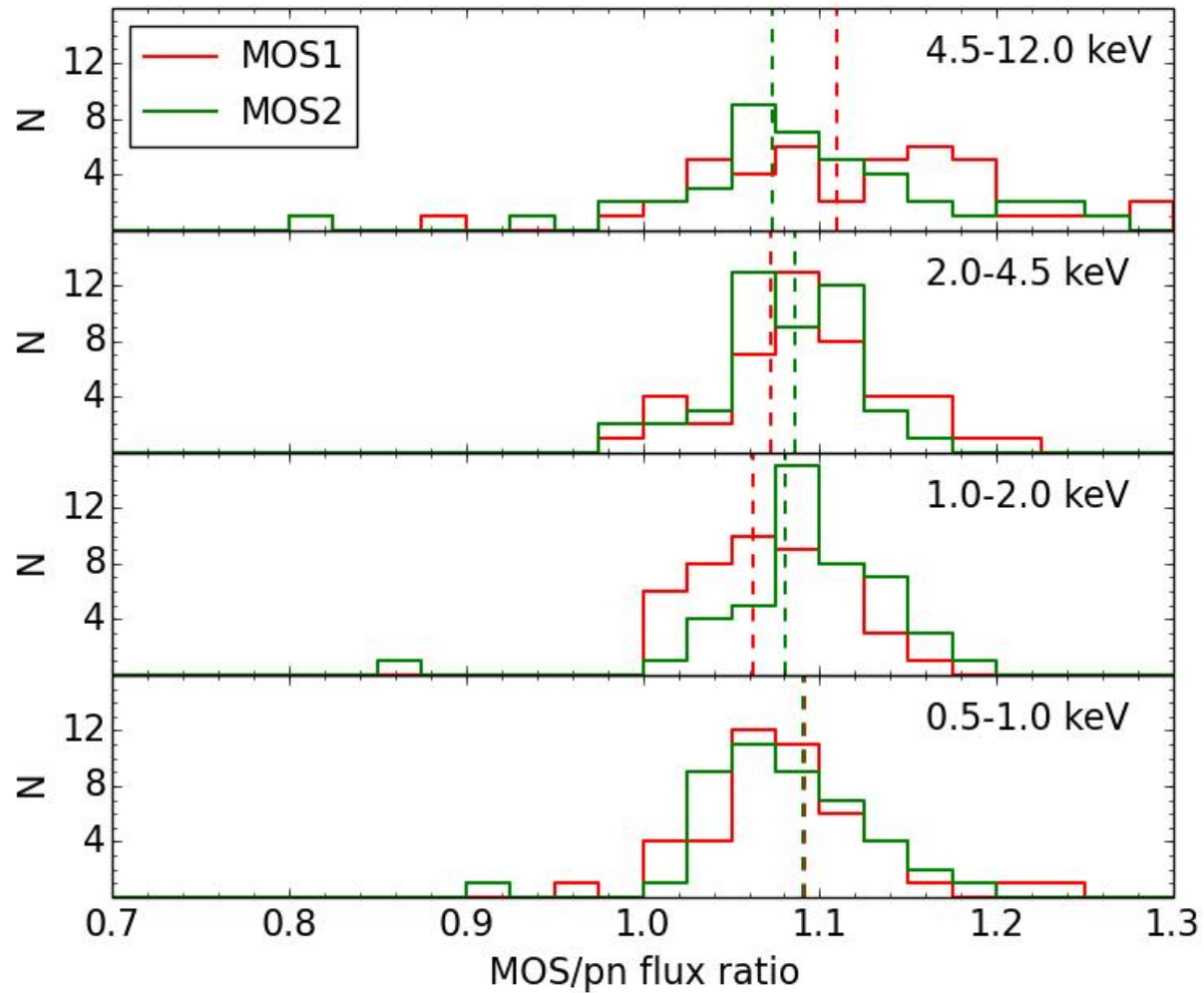


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1 Introduction: CORRAREA



sample of 46 sources

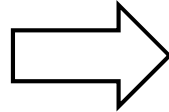
fluxes taken from: XMM-Newton Serendipitous Source Catalogue (3XMM-DR7)



1 Introduction: CORRAREA

- an **empirical correction** of the EPIC **on-axis effective areas** by an energy-dependent **multiplicative factor**, determined by **cross-calibration**
- a non-default option since SAS v14.0 ([Guainazzi et al., 2014](#)): **CORRAREA** = extension of the according constituents in the current calibration files

residual ratio



- stacked residual method
- value for each energy bin would be unity if the cross-calibration of the effective areas was consistent
- reference instrument: pn

→ **GOALS:**

- make it a default empirical correction soon
- automation
- recalibration and further validation



- Original source selection, screening & stacking: [Read et al. \(2014\)](#)
- XMM-Newton Serendipitous Source Catalogue used (3XMM-DR7)

Selection criteria:

- 1.) point-like
- 2.) modes: Full Frame, [Large Window](#), [Small Window](#)
- 3.) filters: Thin, Medium, [Thick](#)
- 4.) # of counts - MOS: > 5000 cts
(0.2 - 12 keV) - pn: > [13500](#) cts
- 5.) count rates - MOS: < [0.7 \(FF\)](#), < 1.5 (LW), < 4.5 (SW)
- pn: < [6 \(FF\)](#), < 0.3 (FFext), < 3 (LW), < 25 (SW)
- 6.) near on-axis (boresight-to-source distance < 2')
- 7.) out of the plane of the Galaxy ($|\text{galactic latitude}| > 15 \text{ deg}$)

- observations with multiple results dismissed (crowded fields)



2 Source Sample

MOS1	MOS2	pn	# obs. 3XMM-DR7
LW	LW	FF	29
“	“	LW	50
“	“	SW	8
SW	SW	FF	15
“	“	LW	9
“	“	SW	55
FF	FF	FF	166
“	“	LW	6
FF	LW	FF	3
FF	SW	FF	2
LW	FF	FF	2
LW	SW	FF	2

→ total: 347 observations



Mainly done via bash, python & idl scripts:

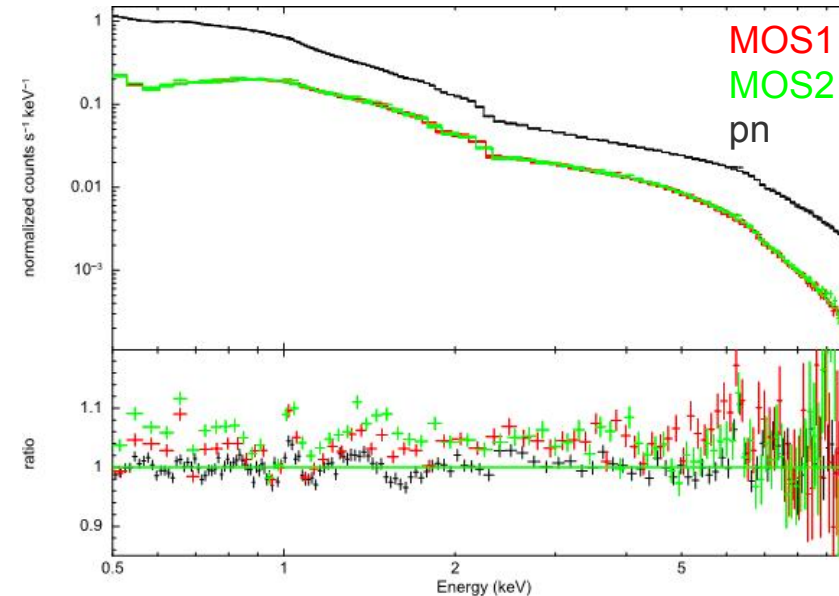
1. initial data processing
2. event files filtered with a **common GTI** file for each observation
3. images for visual screening & background region selection
4. source and background **spectra**, as well as the Redistribution Matrix and Ancillary Response Files (RMFs and ARFs)
5. **stacking** for each detector:
 - source & background spectra: summing up counts per bin, summing up exposures, exposure-weighting BACKSCAL values
 - exposure-weighted RMFs and ARFs
6. phenomenological **reference model** fit to **pn data**:

$$wabs \times [power + power + Gauss + Gauss + Gauss] \times edge$$



7. reference model convolved with the instrument responses of MOS1 and MOS2

pn fit: χ_{red}^2 is 1.08 for 1888 degrees of freedom (calculated with SAS v13.5 and according calibrations)



8. realignment of the residuals to a new, uniform energy grid

9. calculation of the residual ratio α

$$\alpha = \frac{data_i}{model_{pn} \otimes response_i} \times \frac{model_{pn} \otimes response_{pn}}{data_{pn}}$$

i : MOS indices (1, 2)



10. fitting of the residual ratio

current CORRAREA function:

$$R_i(E) = a_i + a_{\text{pn}} + b_i \times e^{-c_i \times e^{-d_i \times E}}$$

R_i : MOS to pn empirical correction factor

i : MOS indices (1, 2)

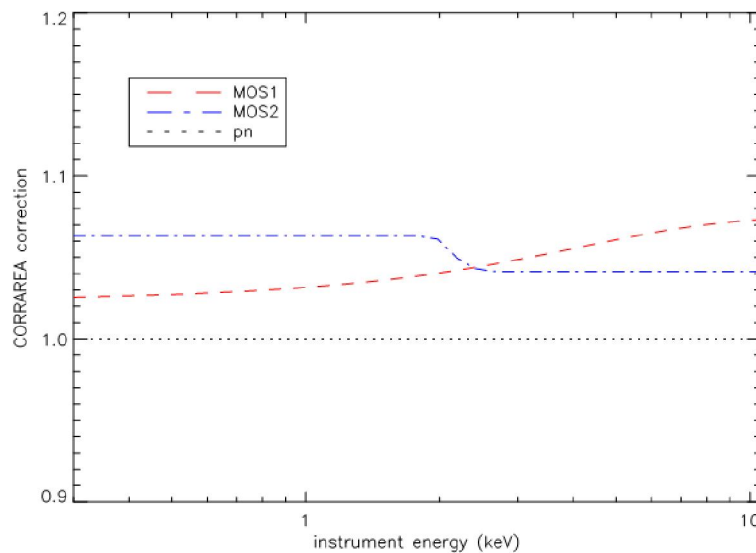
E : energy

$a \dots d$: best fit parameters

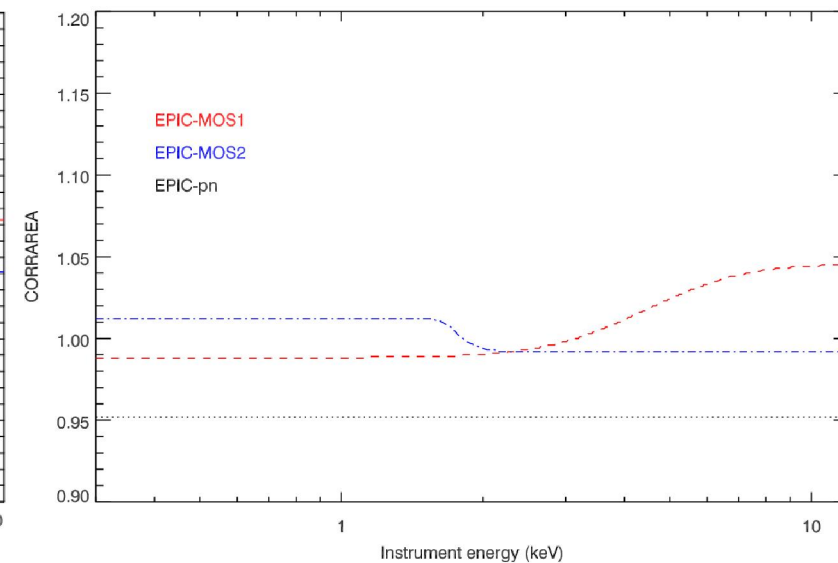
alternative:

$$R_i(E) = a_i + a_{\text{pn}} + b_i \times \frac{1}{1 + \exp\left(\frac{-E + c_i}{d_i}\right)}$$

reproduced:



RN 0321:





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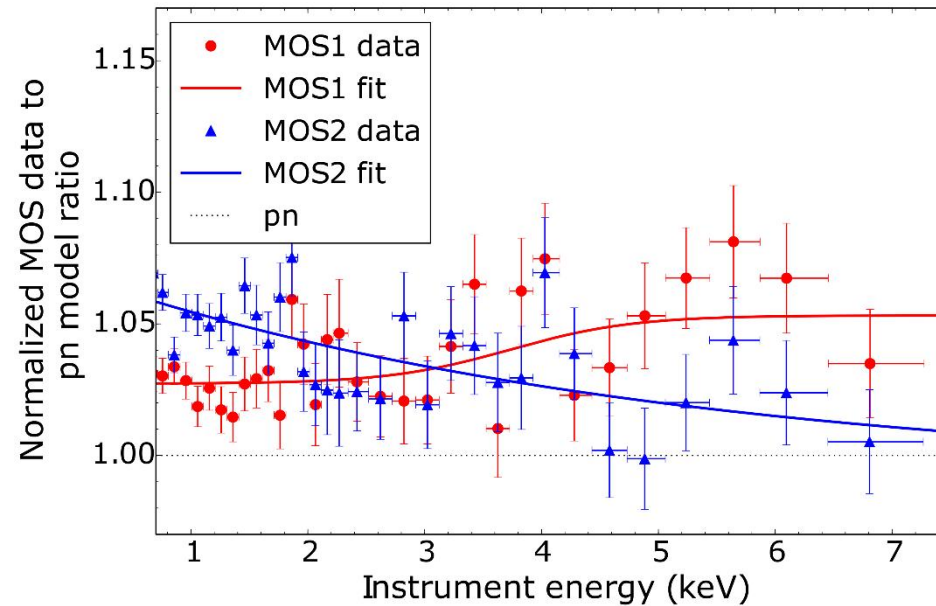
i : MOS indices (1, 2)

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$$R_i(E) = a_i + a_{\text{pn}} + b_i \times \frac{1}{1 + \exp\left(\frac{-E + c_i}{d_i}\right)}$$

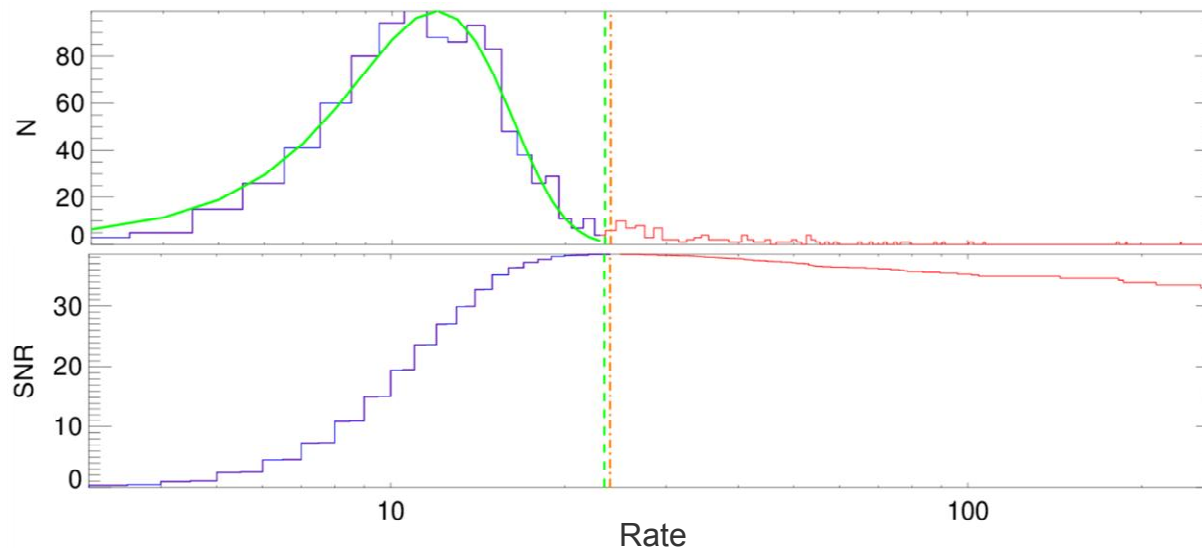




4 Screening

4.1 Good-Time-Intervals

- previously: GTIs uniformly defined as those bins containing less than 130 (pn) or 40 (MOS) counts per bin
- GTIs now individually defined for each observation:
 1. lightcurves with > 10 keV (MOS) or 10-12 keV (pn) are prepared
 2. histogram \rightarrow **gaussian threshold** at $\mu + 3\sigma$
 3. maximum signal-to-noise ratio (snr) \rightarrow **snr threshold**
 4. the more conservative one of the thresholds is chosen



\rightarrow observations with < 1 ks GTI filtered common exposure time are excluded



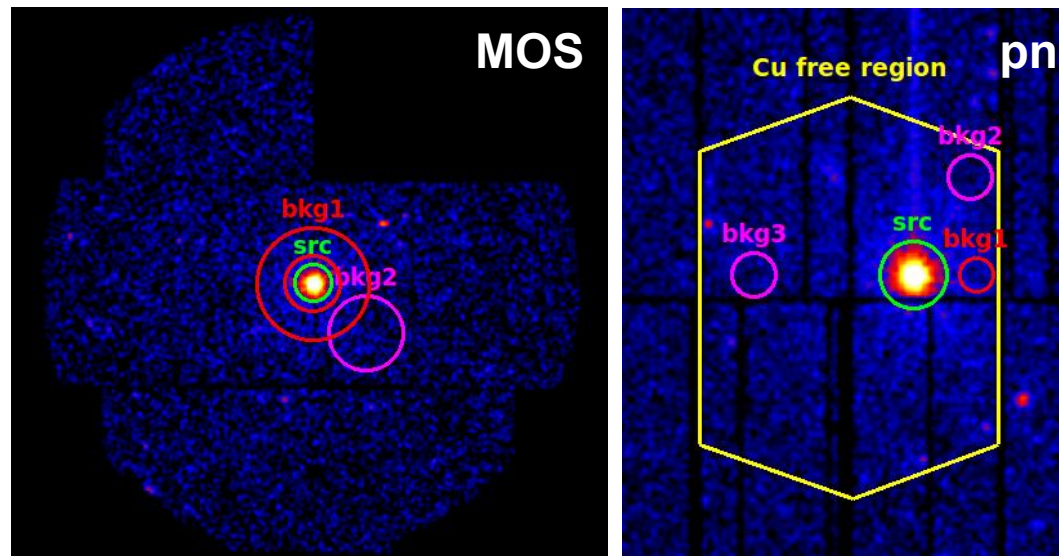
4 Screening

4.2 Image Screening & Background Selection

Images have to be **screened for**:

- crowded fields
- chip gaps & bad CCD columns close to the source
- targets appearing extended or lying within extended emission
- a chip loss of an entire detector chip or quadrant
- maximum source extraction radius

Background selection: FF mode





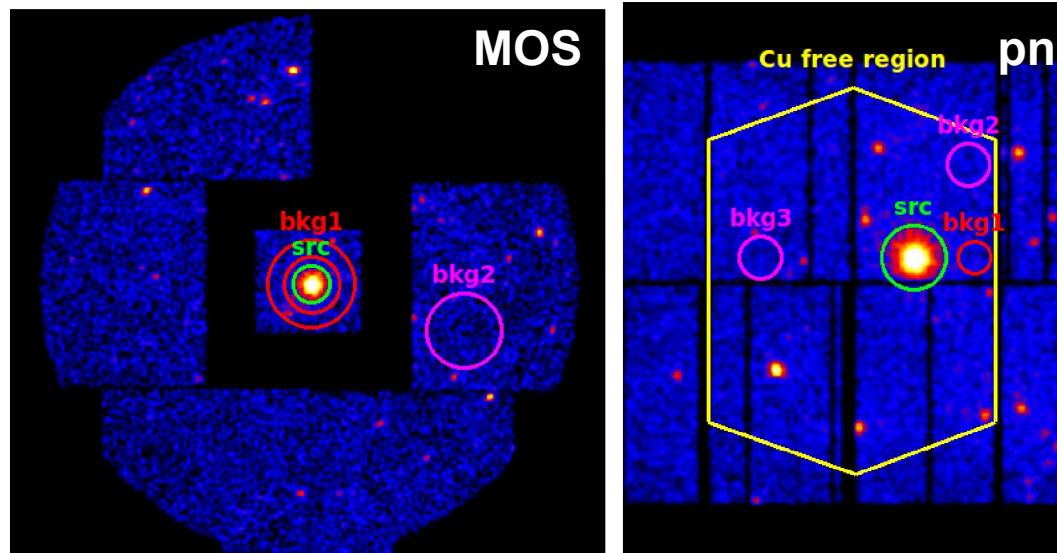
4 Screening

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Images have to be **screened for**:

- crowded fields
- chip gaps & bad CCD columns close to the source
- targets appearing extended or lying within extended emission
- a chip loss of an entire detector chip or quadrant
- maximum source extraction radius

Background selection: LW mode





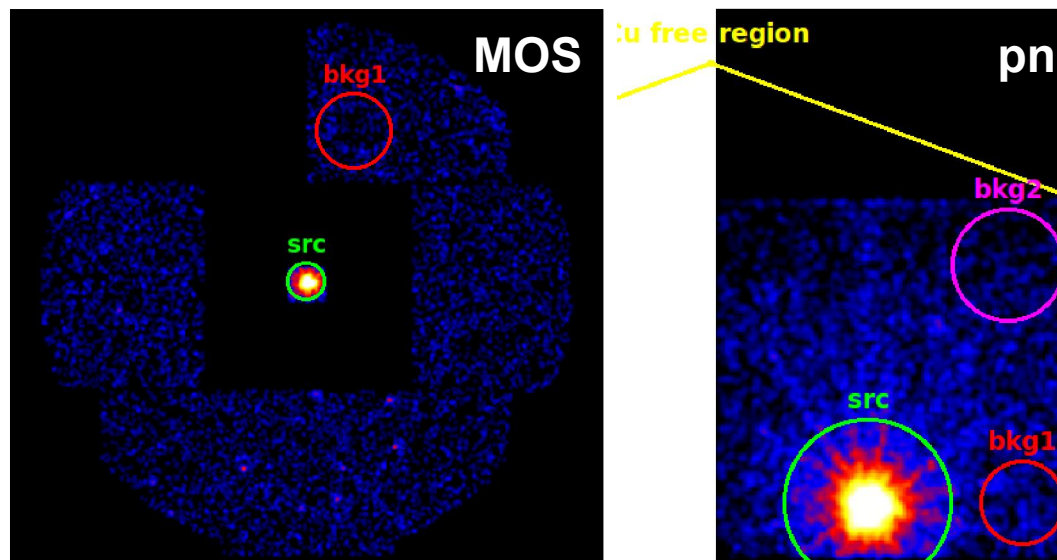
4 Screening

4.2 Image Screening & Background Selection

Images have to be **screened for**:

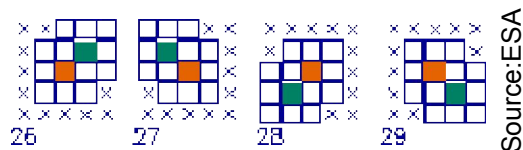
- crowded fields
- chip gaps & bad CCD columns close to the source
- targets appearing extended or lying within extended emission
- a chip loss of an entire detector chip or quadrant
- maximum source extraction radius

Background selection: SW mode

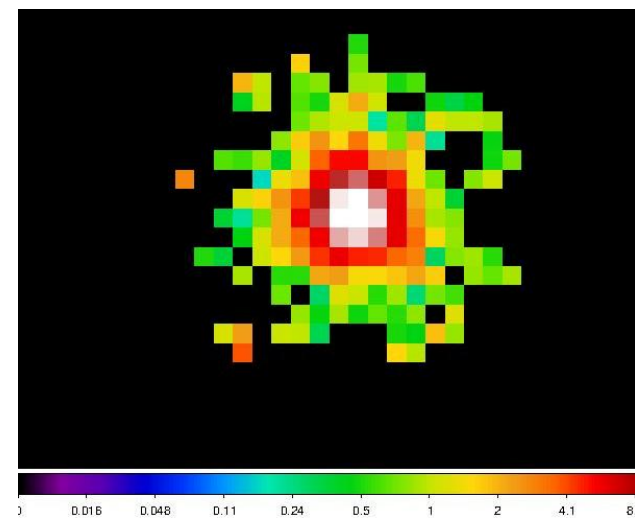




- so far: maximum count rate (as in XMM-Newton Users Handbook v.2.10) given as a source selection criterium to limit pile-up
- more precise method: MOS diagonal events are produced almost exclusively from the pile-up of two single pixel events



- fraction of diagonal events obtained by dividing an image of diagonal events by an image of ‘clean’ events
- not always a clear center; the maximum value is not necessarily in the center; which value to take as the pile-up limit

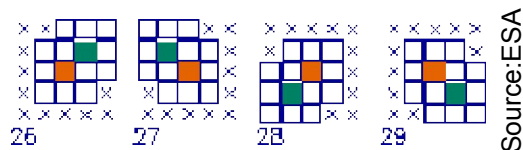




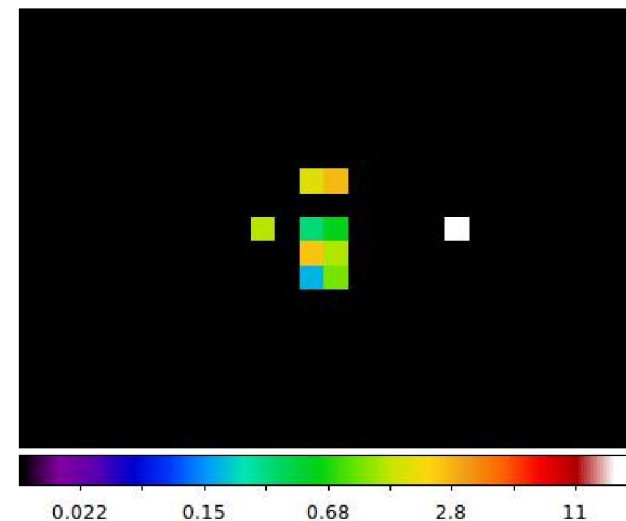
4 Screening

4.3 Pile-Up Check

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- the **automation** to get the residual ratio and the correction function is **done to a large degree** ✓
- the **selection criteria & screening** have been revised ✓
- 3XMM-DR7 brought up **301 new potential observations** ✓
- **update** with SAS v16.1 and according calibration files:
 - initial data **reduction** ✓
 - **GTI** filtering ✓
 - **image screening** and **background region selection** (✓)
 - checking for **pile-up**
 - creating the spectra, stacking them & fitting the **stacked spectrum**
 - calculating the **residual ratio** & deciding on a **correction function** (compare different source extraction radii, pile-up levels, modes, filters)

Thank you!